

Notice of References Cited	Application/Control No. 10/725,239		Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Michael D Masinick		Art Unit 2125	Page 1 of 1



U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,308,107 B1	10-2001	Conboy et al.	700/121
	B	US-6,748,287 B1	06-2004	Hagen et al.	700/99
	C	US-6,564,113 B1	05-2003	Barto et al.	700/99
	D	US-6,725,113 B1	04-2004	Barto et al.	700/99
	E	US-6,535,778 B2	03-2003	Okabe et al.	700/112
	F	US-2003/0171972 A1	09-2003	Heskin, James	705/9
	G	US-6,049,742 A	04-2000	Milne et al.	700/99
	H	US-4,802,094	01-1989	Nakamura et al.	700/115
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	"Shifting Bottleneck Detection" - Roser et al, Toyota Central Research and Development Labs, 2002 Winter Simulation Conference			
	V	"Semiconductor Factory Automation: Designing for Phased Automation" - Gardner et al, Hewlett-Packard Corporation, IEEE 1996			
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.